

Frequency-Dependent Target Impedance Method Fulfilling Both Average and Dynamic Voltage Drop Constraints

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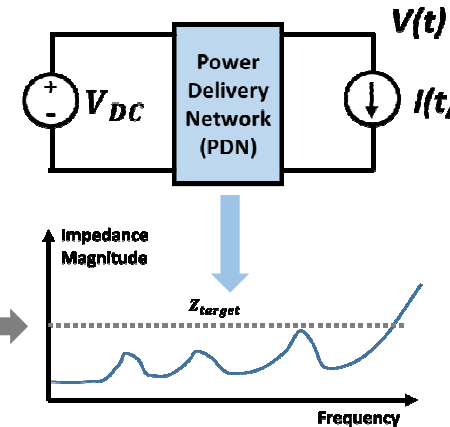
Agenda

- **Background of Target Impedance**
 - Challenges for target impedance
 - Contribution of this work
- **Frequency-Dependent Target Impedance**
 - Target impedance deriving flow
 - Magnitude equivalent frequency (MEF)
 - Synthesize target impedance
- **Experiment Results**
- **Conclusion**

Background of target impedance

PDN uses target impedance to ensure maximum allowed voltage drop^[1]

$$Z_{target} = \frac{V_{allowed_drop}}{I}$$



Flat Z_{target} is increasingly difficult to meet

Cause under- or over-designed PDN.

Frequency-dependent $Z_{target}(f)$ is an open problem.

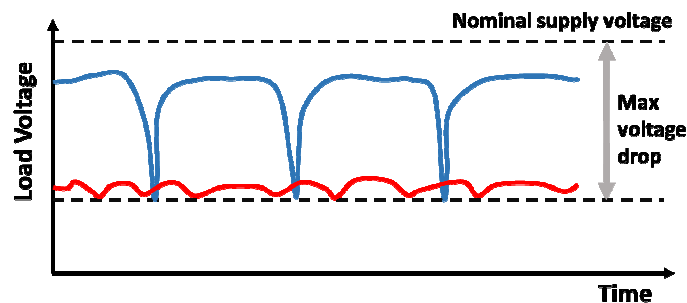
Requirement and challenge

Consider **average** and **dynamic voltage drop** constraints.

Associate **frequency-domain Z_{target}** and **time-domain I, V** .

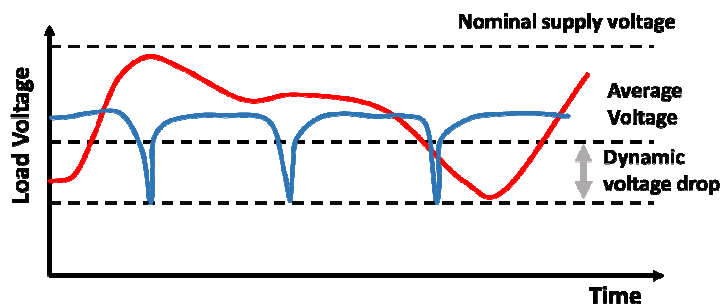
[1] L. D. Smith, et al., "Power Distribution System Design Methodology and Capacitor Selection for Modern CMOS Technology", IEEE Trans. Advanced Packaging, vol. 22, no. 3, pp. 284-291, 1999.

Average and dynamic voltage drop constraints are NOT well considered in previous work.



Given one voltage drop constraint, PDN can be **over- or under-designed**.
blue needs more focus on **dynamic drop**.
red needs more focus on **average drop**.

Deriving $Z_{target}(f)$ using current spectrum and voltage spectrum^[2] has limitation.



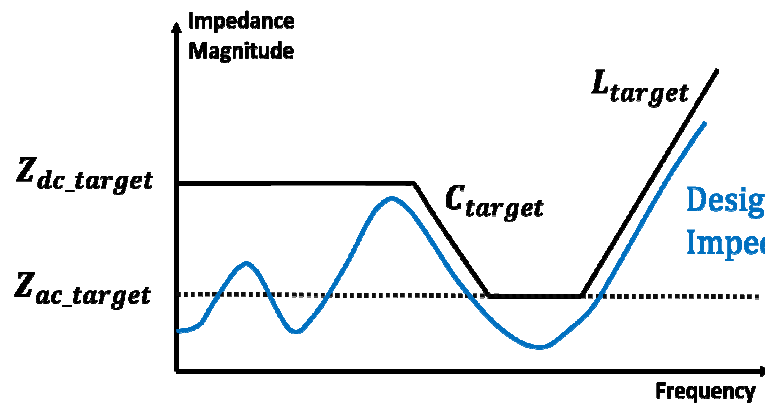
Converting voltage drop constraints to voltage spectrum has many **variations**.
(blue and red with same constraints)
 $Z_{target}(f)$ is not unique

[2] D. Oh, Y. Shim, "Power integrity analysis for core timing models", Proc. Int'l Symposium on EMC, pp. 833-838, Aug. 2014.

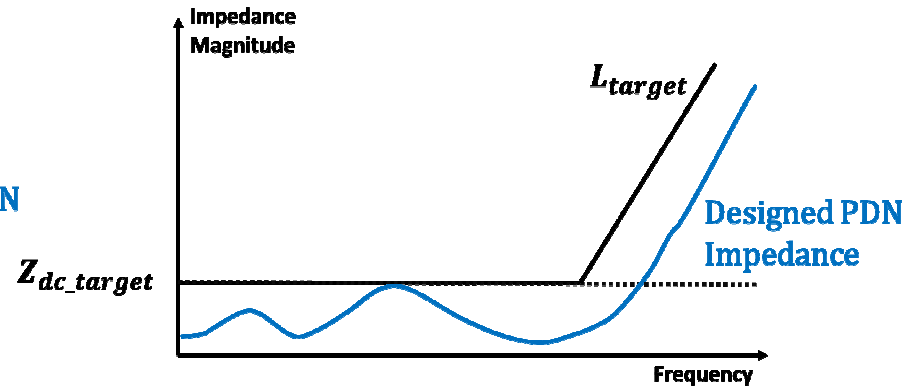
Contribution of this work

1. Fulfills both average and dynamic voltage drop constraints.

Two Z_{target} types for different constraints focus.



Dynamic voltage drop
is main design focus



Average voltage drop
is main design focus

2. Associates time-domain I , V with frequency-domain Z_{target} .

By idea of Magnitude Equivalent Frequency (MEF).

Verified result by synthesized Z_{target} circuit.

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Target impedance deriving flow

Inputs:

Load current profile $I(t)$

Voltage drop constraints V_{avg_allow} and V_{dyn_allow}

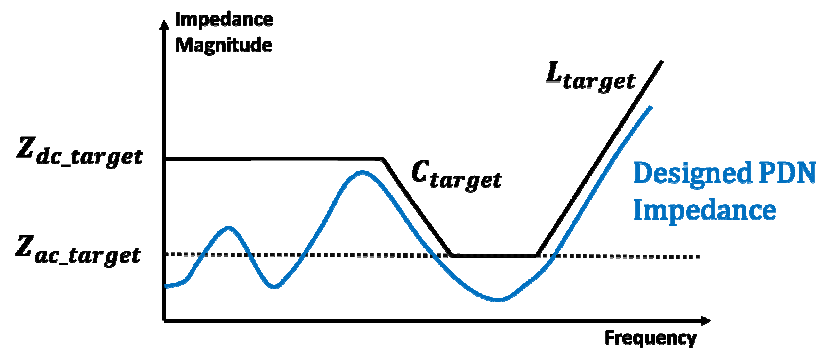
Frequency-dependent Z_{target} is composed of:

Z_{ac_target} : target impedance at middle-high frequency

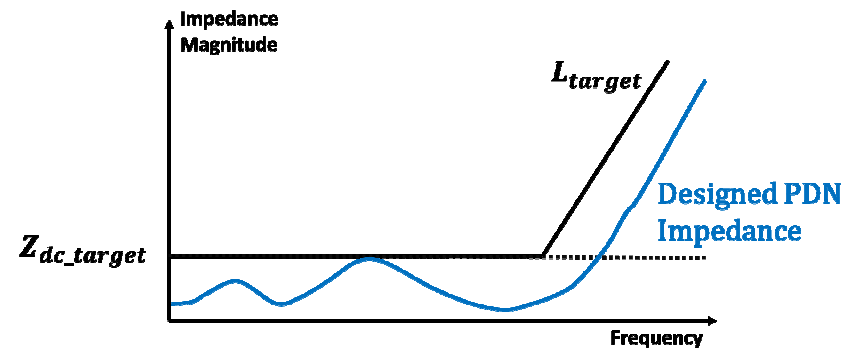
Z_{dc_target} : target impedance at low frequency

C_{target} : target capacitance, min required capacitance

L_{target} : target inductance, max allowed inductance



V_{dyn_allow} is main design focus

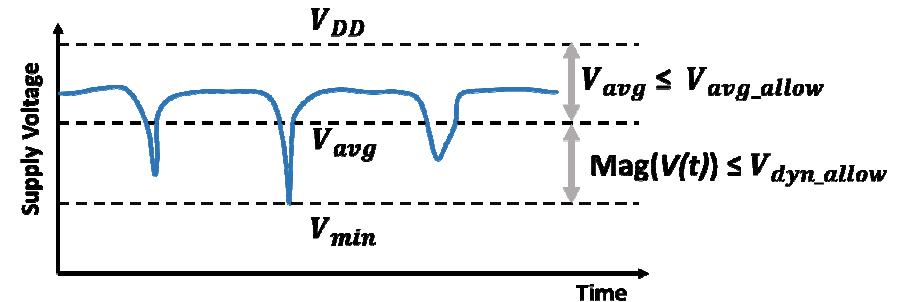


V_{avg_allow} is main design focus

Derive Z_{ac_target} and Z_{dc_target}

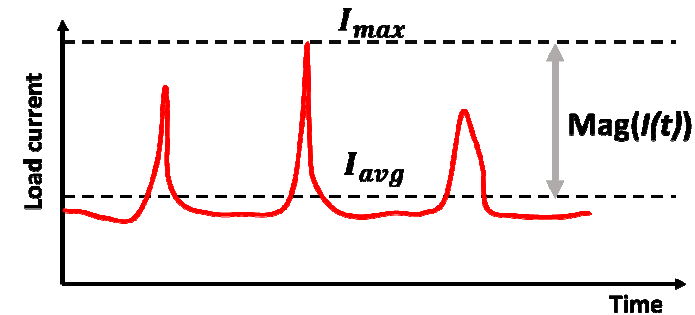
Consider V_{avg_allow} constraints:

$$Z_{dc_target} = V_{avg_allow} / I_{avg}$$



Consider V_{dyn_allow} constraints:

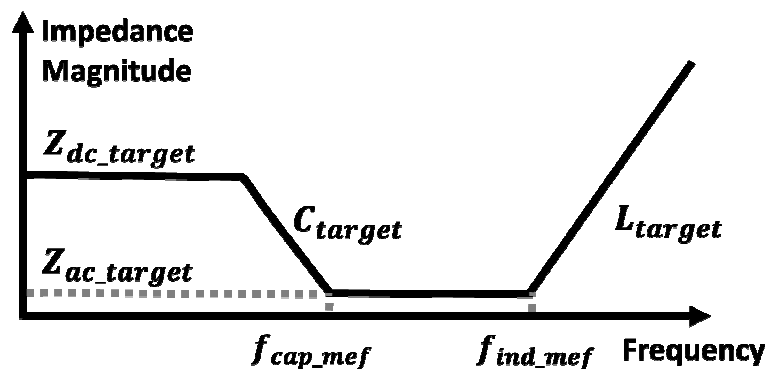
$$Z_{ac_target} = V_{dyn_allow} / Mag(I(t))$$



Result in piecewise Z_{target} shapes:

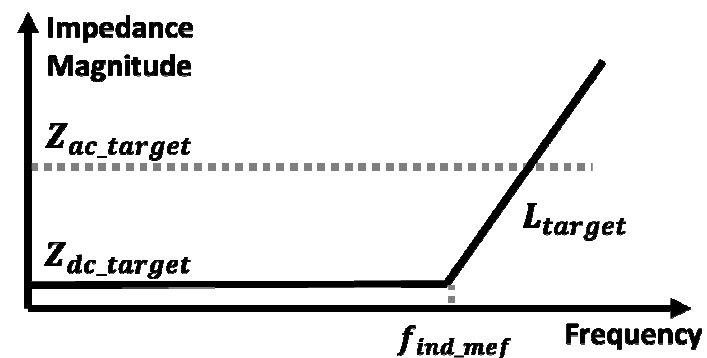
$$Z_{ac_target} < Z_{dc_target}$$

V_{dyn_allow} drop is design focus



$$Z_{ac_target} \geq Z_{dc_target}$$

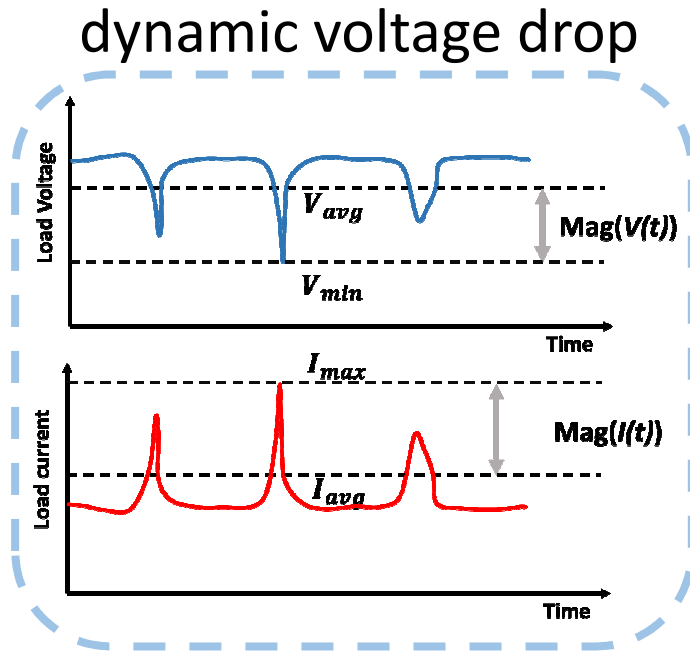
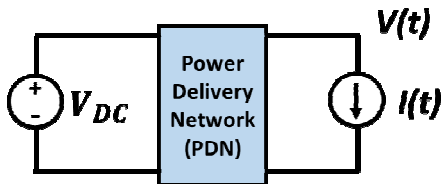
V_{avg_allow} drop is design focus



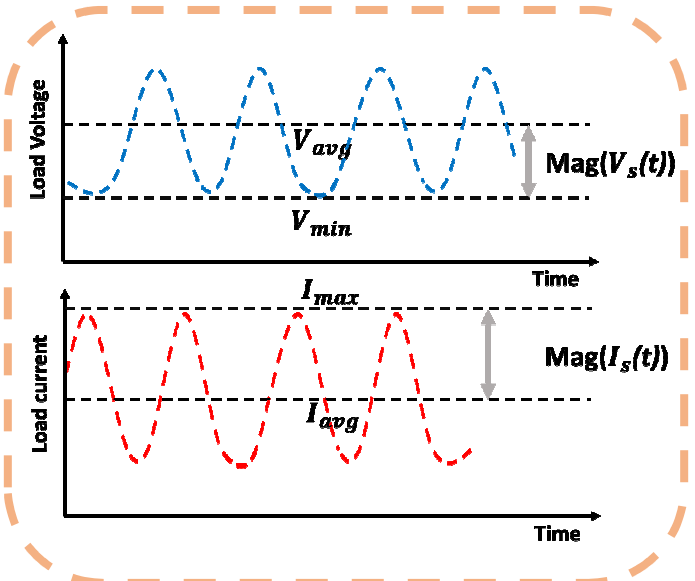
Magnitude equivalent frequency (MEF) I

can be represented by

If impedance is
C dominated
 or
L dominated



sine current with **MEF**



L dominant impedance example:

$$\text{Let } I_s(t) = \text{Mag}(I(t)) \sin(2\pi f_{MEF}t),$$

$$\text{Mag}(I_s(t)) = \text{Mag}(I(t))$$

$$\text{Then } \text{Mag}(V_s(t)) = \text{Mag}\left(L \frac{dI_s}{dt}\right) = \cancel{L} 2\pi f_{MEF} \text{Mag}(I(t))$$

$$\text{Can equal to: } \text{Mag}(V(t)) = \text{Mag}\left(L \frac{dI}{dt}\right) = \cancel{L} \text{Mag}\left(\frac{dI}{dt}\right)$$

*Similar with **C** dominant impedance.

Magnitude equivalent frequency (MEF) II

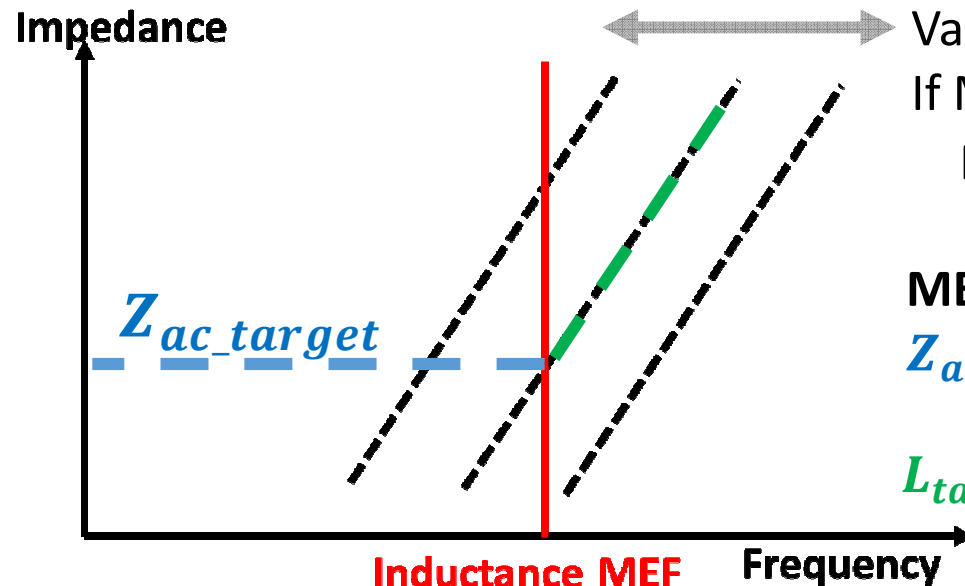
With **different** L or C , MEF sine current can still replay the **dynamic voltage drop**. (equations still hold with same MEF)

$$\text{Mag}(I_s(t)) = \text{Mag}(I(t))$$

$$\text{Mag}(V_s(t)) = \text{Mag}(V(t))$$

Since L and C are common coefficient and can be canceled out in equations.

Use MEF to find L_{target} (max allowed inductance):



Varying L for an impedance,
If $\text{Mag}(V_s(t)) = V_{dyn_allow}$ at MEF,
 $\text{Mag}(V(t)) = V_{dyn_allow}$ also holds.

MEF serves as **corner frequency** of
 $Z_{ac_target} = V_{dyn_allow} / \text{Mag}(I(t))$

$$L_{target} = \frac{Z_{ac_target}}{2\pi f_{ind_mef}}$$

Magnitude equivalent frequency (MEF) III

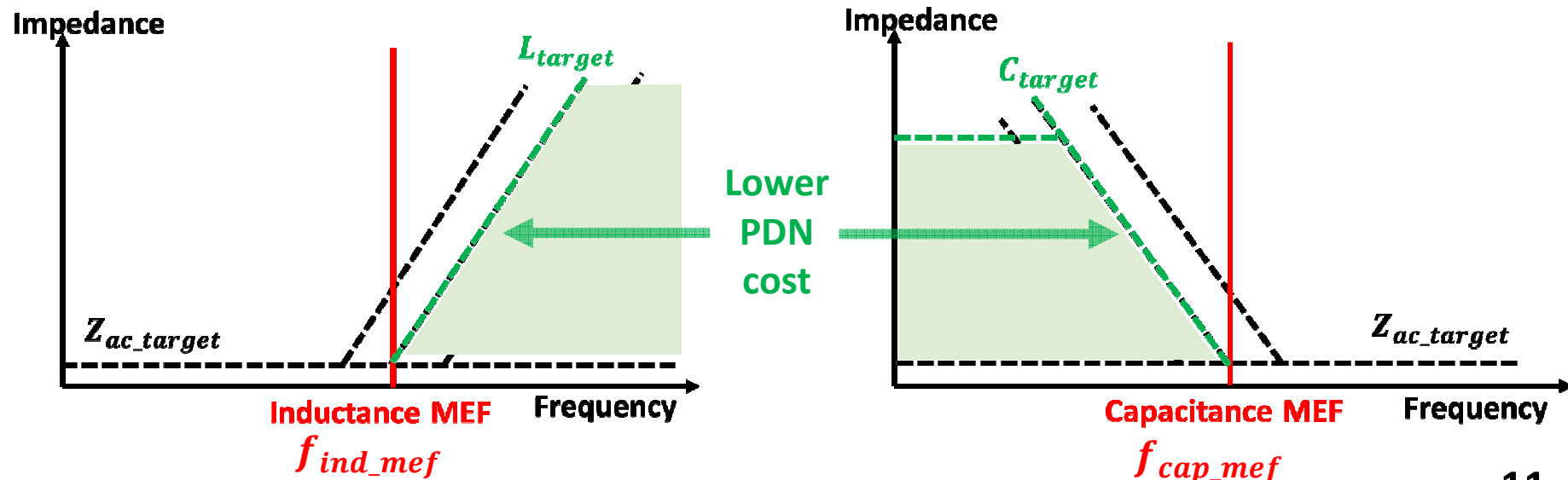
Z_{target} design method is simplified because:

Original current profile (with complex spectrum and profile)

Replaced by **MEF sine** profile (with one spectrum component).

Use **MEF** to find L_{target} (Max allowed inductance).

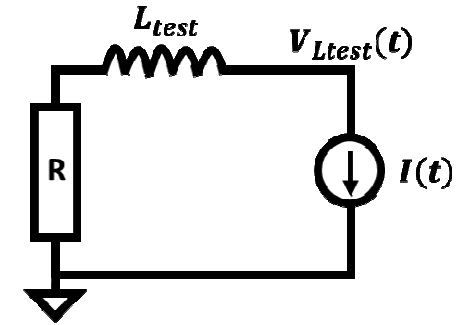
C_{target} (Min required capacitance).



Calculate MEF, L_{target} , and C_{target}

Characterization Circuit Setup:

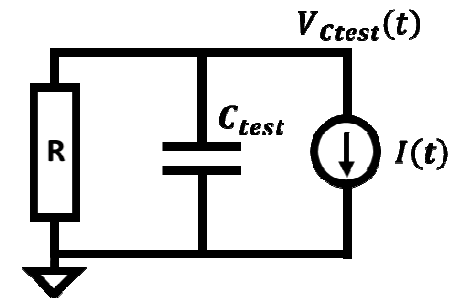
R , L_{test} , C_{test} are **known-value** parameters.
Form L and C dominant impedance.



For inductance MEF

Characterization Flow:

Inject $I(t)$ run simulation for $V_{Ltest}(t)$ and $V_{Ctest}(t)$.
Measure $\text{Mag}(I(t))$, $\text{Mag}(V_{Ltest}(t))$, and $\text{Mag}(V_{Ctest}(t))$.



For capacitance MEF

Inductance MEF is obtained by:

$$f_{ind_mef} = \frac{\text{Mag}(V_{Ltest}(t))}{\text{Mag}(I(t))} \frac{1}{2\pi L_{test}}$$

Target inductance:

$$L_{target} = \frac{Z_{ac_target}}{2\pi f_{ind_mef}}$$

Capacitance MEF is obtained by:

$$f_{cap_mef} = \frac{\text{Mag}(I(t))}{\text{Mag}(V_{Ctest}(t))} \frac{1}{2\pi C_{test}}$$

Target capacitance:

$$C_{target} = \frac{1}{2\pi f_{cap_mef} Z_{ac_target}}$$

Synthesize Z_{target} circuit

T-shape RLC circuit to track Z_{target} .

Direct using Z_{dc_target} , Z_{ac_target} , C_{target} , L_{target}

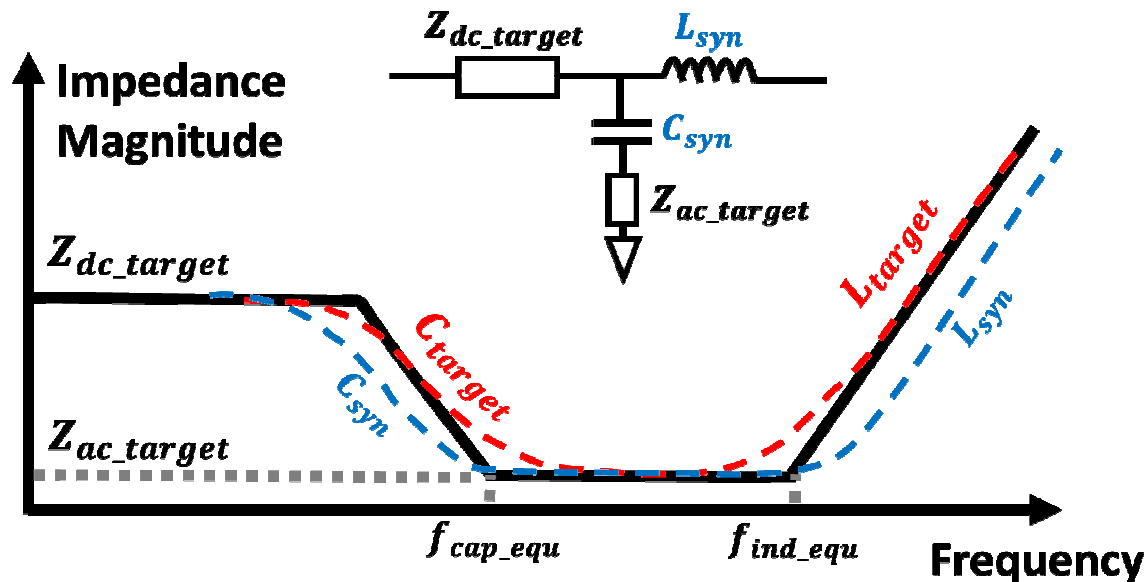
Can violate the voltage drop constraints.

(Actual impedance is larger at **corner frequency**)

In the experiment:

Use **larger capacitance and smaller inductance.**

Other synthesis method can be applied also.



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Experiment setup

Nominal voltage is 800 mV.

Case 1 : reference 1.0 GHz sine profile.

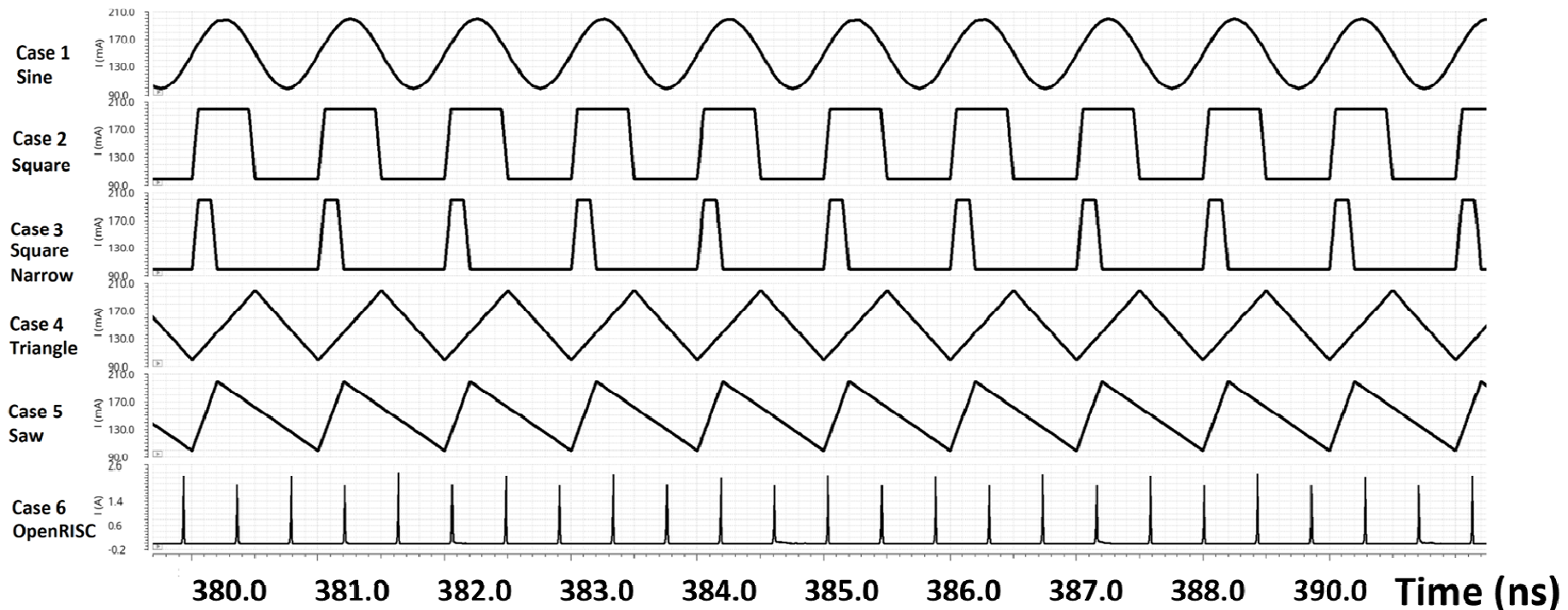
Case 2 and 3: square current profile to mimic module activations.

Case 4 and 5: triangle current profile to mimic typical digital circuit load.

The constraints are $V_{avg_allow}=70$ mV and $V_{dyn_allow}=10$ mV.

Case 6: current profile from OpenRISC operation (15nm Open Cell Lib, 1.2 GHz)

The constraints are $V_{avg_allow}=10$ mV and $V_{dyn_allow}=30$ mV.



Experiment results

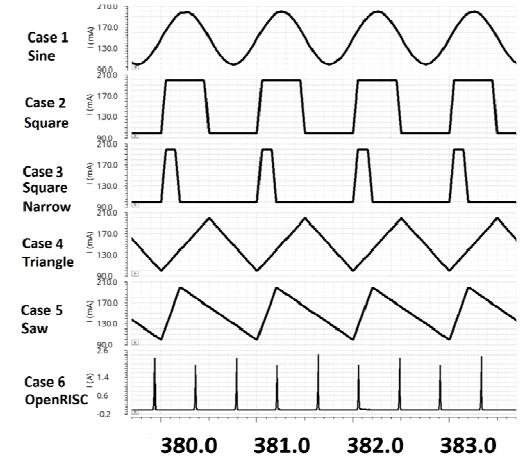
Measured V_{avg} and V_{min} correlates well with constraints.

Average difference rates are 0.0003% and 0.3%

The derived target impedance associates with current profile.

Wider pulse results in larger C_{target}

Sharper slope result in smaller L_{target}



	Z_{dc_target} (mΩ)	Z_{ac_target} (mΩ)	C_{target} (nF)	L_{target} (pH)	V_{avg} (mV)	V_{min} (mV)
Case 1	466.6	200.0	0.8	31.8	730.0	722.5
Case 2	482.7	181.8	1.2	5.0	730.0	722.2
Case 3	608.7	117.6	0.7	5.0	729.9	720.9
Case 4	466.6	200.0	0.6	24.7	730.0	722.5
Case 5	466.6	200.0	0.5	19.8	730.0	722.5
Avg. Diff.	-	-	-	-	0.0003%	0.3%
Case 6	251.9	12.5	0.35	0.01	790.2	760.6
Diff.	-	-	-	-	0.02%	0.07%

Conclusion

- **A new frequency-dependent target impedance method.**
- **Consider both average and dynamic voltage drop constraints.**
- **Associate time domain and frequency domain info with MEF.**
- **Synthesized target impedance correlates well with constraints.**

Q & A

